

**Prénom : Thomas**

**Nom : BEGOU**

**Liste de Publications 2009-2013 :**

A. Granier, T. Begou, K. Makaoui, A. Soussou, B Bêche, E. Gaviot, M.P. Besland et A. Goulet, "Influence of ion bombardment and annealing on the structural and optical properties of TiOx thin films deposited in inductively coupled TTIP/O2 plasma", Plasma Processes and Polymers, 2009, vol. 6, pp. S741-S745.

S. A. Little, T. Begou, R. W. Collins et S. Marsillac, "Temperature dependence of silver nanoparticles dielectric function as observed by in situ and real time spectroscopic ellipsometry", Applied Physics Letters, 100 (2012) 051107.

T. Begou, V. Ranjan, R. W. Collins et S. Marsillac, "Optical detection of melting point depression for silver nanoparticles via in situ real time spectroscopic ellipsometry" Applied Physics Letters 100 (2012) 051107

**Liste de Communications 2009-2013 :**

T. Begou, S.A. Little, A. Aquino, V. Ranjan, A. Rockett, R.W. Collins, S. Marsillac, "In Situ and Ex Situ Characterization of (Ag,Cu)InSe2 thin films", 37th IEEE Photovoltaic Specialists Conference, Seattle (USA), 19-24 Juin 2011, poster.

V. Ranjan, T. Begou, S. Little, D. Attygalle, R.W. Collins, S. Marsillac "Investigation of the growth process and optical transitions as a function of Ga content in CuIn1-xGaxSe2 thin films at 570°C", 37th IEEE Photovoltaic Specialists Conference, Seattle (USA), 19-24 Juin 2011, poster.

T. Begou, C. Hecquet, F. Lemarchand et M. Lequime, "All dielectric broadband mirror for Fabry-Perot interferometer", Optical Interference Coating (OIC), Whistler (Canada), 16-21 juin 2013, PTE 6, session postdeadline.

**Collaborations (nationales et/ou internationales) avec d'autres laboratoires de Recherche :**

Postdoctorat d'un an (2010-2011) à Old Dominion University – Electrical and Computer Engineering Department – Norfolk, VA – USA (responsable: S. Marsillac).